

## Example 3: Maximizing Yield through Probecard Performance Analysis

### Finding the Issue

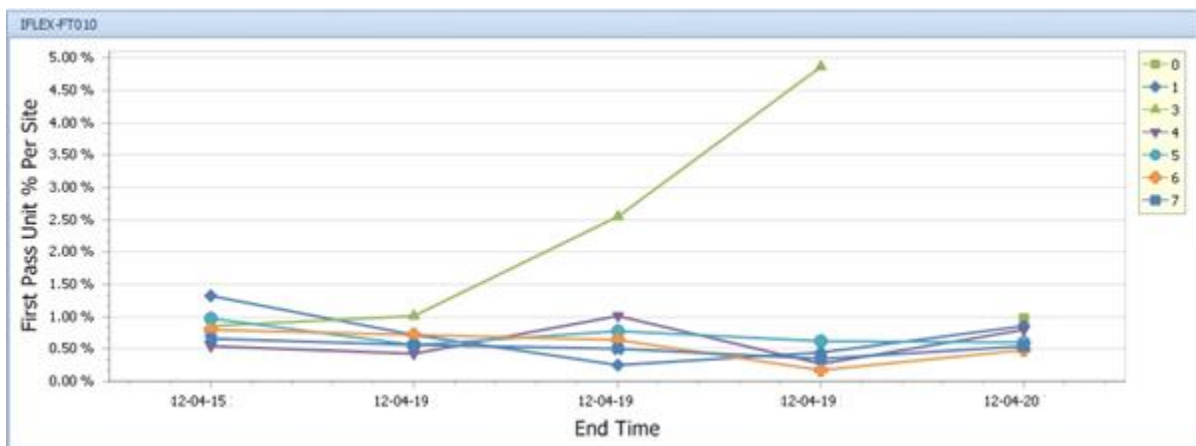
A high-level product-based report shows that a product is achieving lower than expected yield and higher than expected retest rates.

### Performing the Analysis

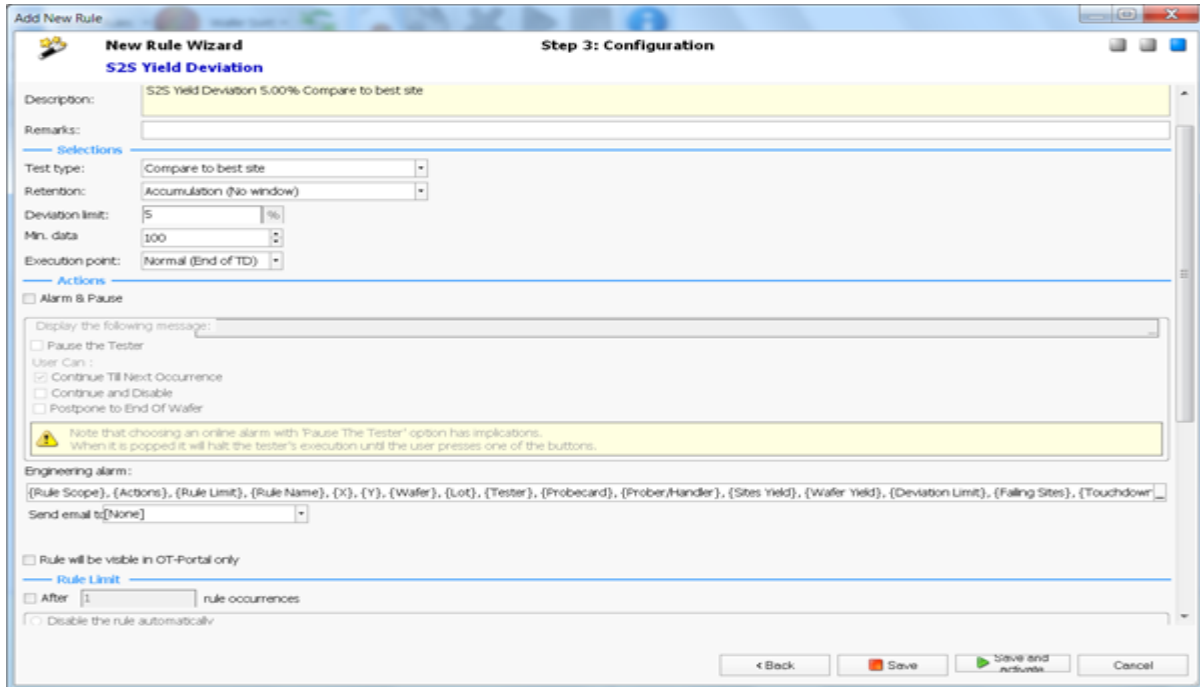
By drilling down to individual tester performance within the Optimal+ solution the engineer is able to identify a specific probe card, which is causing the issue within a matter of minutes. The test house is notified and the probe card is removed for inspection.

### Preventing Future Recurrences

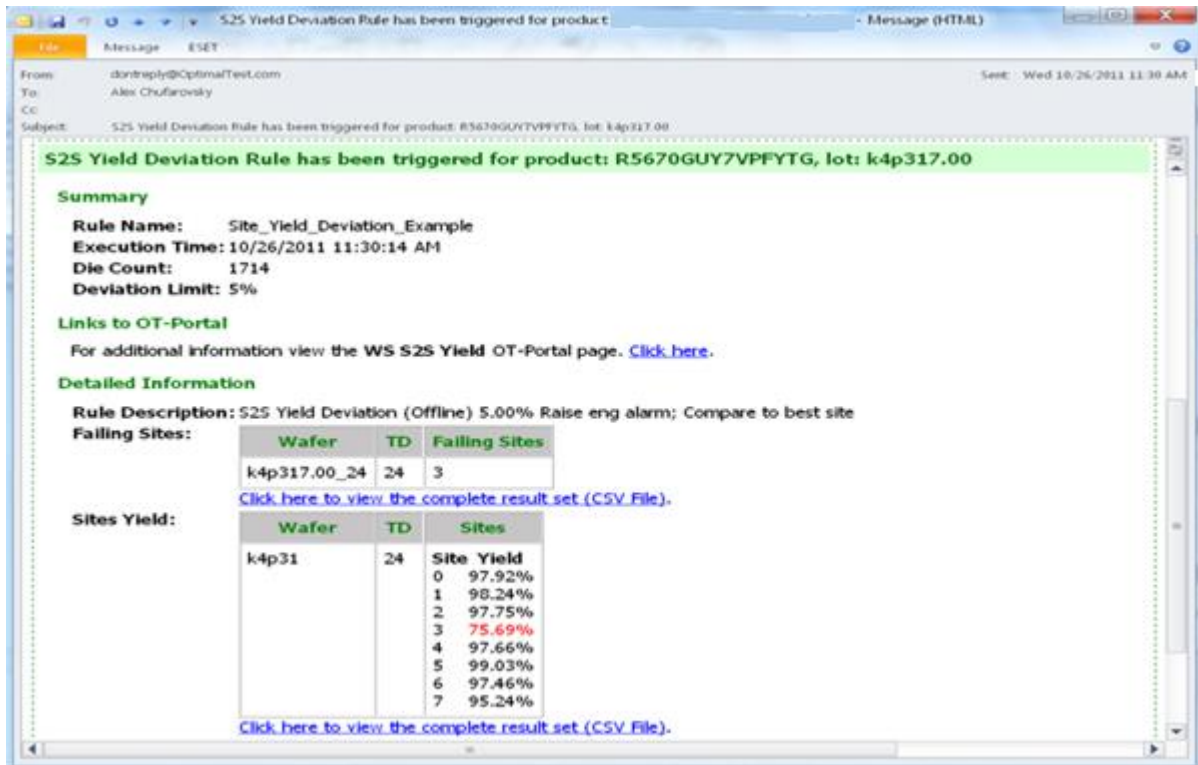
A rule is created to automatically catch lots exhibiting high site-to-site yield discrepancies. The next time this problem occurs, an email alert can immediately be sent to the user so that the problem can be immediately resolved.



**Step 1** – Analyzing a probecard shows site 3 with consistently low yield



Step 2 – Creating a rule to catch site-to-site deviations for this product



Step 3 – Receiving an alert when the problem next occurs